

Notice of References Cited

Application/Control No.

10/574,367

Applicant(s)/Patent Under
Reexamination
JUTTE ET AL.

Examiner

VAN T. PHAM

Art Unit

2627

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,815,059 A	03-1989	Nakayama et al.	369/44.24
*	B	US-5,260,828 A	11-1993	Londono et al.	359/565
*	C	US-5,627,847 A	05-1997	Leger, James R.	372/9
*	D	US-5,978,148 A	11-1999	Oono et al.	359/668
*	E	US-6,072,579 A	06-2000	Funato, Hiroyoshi	356/457
*	F	US-6,084,844 A	07-2000	Takeda, Tadashi	369/112.1
*	G	US-6,154,326 A	11-2000	Ueyanagi et al.	359/819
*	H	US-6,191,889 B1	02-2001	Maruyama, Koichi	359/566
*	I	US-6,327,241 B1	12-2001	Boutaghou et al.	369/300
*	J	US-7,301,881	11-2007	Itonaga, Makoto	369/112.23
*	K	US-2003/0026190 A1	02-2003	Hendriks et al.	369/112.28
*	L	US-6,590,708 B2	07-2003	Nakai et al.	359/558
*	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.